

# Search Notes



Application/Control No.

10/589,145

Examiner

Hien D. Vu

Applicant(s)/Patent under Reexamination

THIEL ET AL.

Art Unit

2833

## SEARCHED

Class	Subclass	Date	Examiner
439	82	8/9/07	R
↓	83	↓	↓
↓	78	↓	↓
↓	80	↓	↓
↓	84	↓	↓

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR